

High Speed IGBT3 Chip

Features:

- 650V Trench & Field Stop technology
- high speed switching series third generation
- low V_{CE(sat)}
- low EMI
- low turn-off losses
- positive temperature coefficient
- qualified according to JEDEC for target applications

Recommended for:

 discrete components and modules

Applications:

- uninterruptible power supplies
- welding converters
- converters with high switching frequency



Chip Type	V _{CE}	<i>I</i> _{Cn} ¹⁾	Die Size	Package
IGC54T65R3QE	650V	100A	5.97 x 8.97 mm ²	sawn on foil

¹⁾ nominal collector current at Tc = 100°C, not subject to production test - verified by design/characterization

Mechanical Parameters

Die size		5.97 x 8.97		
Emitter pad size		See chip drawing	mm^2	
Gate pad size		1.615 x 0.817] """	
Area total		49.81		
Thickness		70	μm	
Wafer size		200	mm	
Max.possible chips per wafer		486		
Passivation frontside		Photoimide		
Pad metal		3200 nm AlSiCu		
Backside metal		Ni Ag –system		
Die bond		Electrically conductive epoxy glue and soft solder		
Wire bond		Al, <500μm		
Reject ink dot size		Ø 0.65mm ; max 1.2mm		
Storage environment	for original and sealed MBB bags	Ambient atmosphere air, Temperature 17°C – 25°C, < 6 month		
Storage environment	for open MBB bags	Acc. to IEC62258-3: Atmosphere >99% Nitrogen or inert gas, Humidity <25%RH, Temperature 17°C – 25°C, < 6 month		



Maximum Ratings

Parameter	Symbol	Value	Unit
Collector-Emitter voltage, $T_{\rm vj}$ =25 °C	V _{CE}	650	V
DC collector current, limited by $T_{\rm vjmax}$	Ic	1)	Α
Pulsed collector current, t_p limited by $T_{vj \max}^{2}$	I _{c,puls}	300	Α
Gate emitter voltage	V _{GE}	±20	V
Operating junction temperature	T _{vj}	-40 +175	°C
Short circuit data $^{2) \ 3)} \ V_{GE} = 15V, \ V_{CC} = 400V, \ T_{vj} = 150 ^{\circ}C$	tsc	5	μs

¹⁾ depending on thermal properties of assembly

Static Characteristics (tested on wafer), T_{vj} =25 °C

Parameter	Symbol	Conditions	Value			Unit
Tarameter	Cymbol	Conditions	min.	typ.	max.	
Collector-Emitter breakdown voltage	V _{(BR)CES}	$V_{\rm GE}$ =0V , $I_{\rm C}$ =2 mA	650			
Collector-Emitter saturation voltage	V _{CEsat}	V _{GE} =15V, I _C =100A	1.38	1.85	2.22	V
Gate-Emitter threshold voltage	$V_{\rm GE(th)}$	$I_{\rm C}$ =1.6mA , $V_{\rm GE}$ = $V_{\rm CE}$	4.2	5.1	5.6	
Zero gate voltage collector current	I _{CES}	V_{CE} =650V , V_{GE} =0V			5	μA
Gate-Emitter leakage current	I _{GES}	V_{CE} =0V , V_{GE} =20V			150	nA
Integrated gate resistor	r _G			2		Ω

Electrical Characteristics (not subject to production test - verified by design / characterization)

Symbol	Conditions	Value			Unit
		min.	typ.	max.	Oill
W	V_{GE} =15V, I_{C} =100A,		2.25		V
V CEsat	<i>T</i> _{vj} =175 °C		2.25		V
Cies	$V_{CE}=25V$,		6100		
	$V_{GE}=0$ V. $f=1$ MHz				pF
C _{res}	$T_{\rm vj}$ =25 °C		180		
	V _{CEsat}	V_{CEsat} $V_{\text{GE}} = 15 \text{V}, I_{\text{C}} = 100 \text{A},$ $T_{\text{vj}} = 175 ^{\circ}\text{C}$ $V_{\text{CE}} = 25 \text{V},$ $V_{\text{GE}} = 0 \text{V}, f = 1 \text{MHz}$	V_{CEsat} V_{GE} =15V, I_{C} =100A, $I_{\text{V}_{\text{I}}}$ =175 °C I_{CE}	Symbol Conditions min. typ. V_{CEsat} V_{GE} =15V, I_{C} =100A, T_{vj} =175 °C 2.25 C_{ies} V_{CE} =25V, V_{GE} =0V, f =1MHz 6100	Symbol Conditions min. typ. max. V_{CEsat} V_{GE} =15V, I_{C} =100A, T_{vj} =175 °C 2.25 C_{ies} V_{CE} =25V, V_{GE} =0V, I_{CE} =1MHz 6100

Further Electrical Characteristic

Switching characteristics and thermal properties are depending strongly on module design and mounting technology and can therefore not be specified for a bare die.

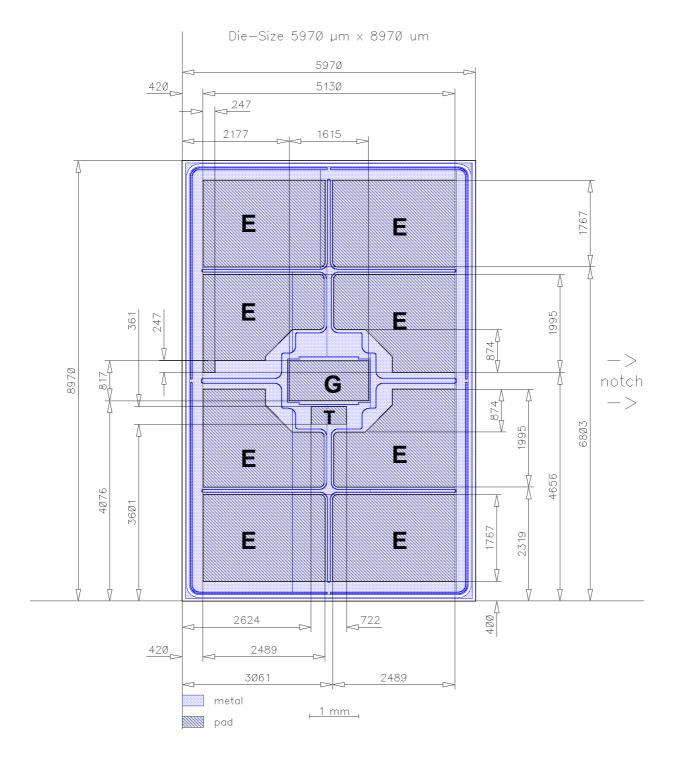
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²⁾ not subject to production test - verified by design/characterization

³⁾ allowed number of short circuits: <1000; time between short circuits: >1s.



Chip Drawing



E = Emitter

G = Gate

T = Testpad

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Description

AQL 0,65 for visual inspection according to failure catalogue

Electrostatic Discharge Sensitive Device according to MIL-STD 883

Revision History

Version	Subjects (major changes since last revision)	Date
2.0	Final data sheet	26.07.2012

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